Attorney's Docket No.: 16696-003001/

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Gunn et al. Art Unit: to be assigned Serial No.: to be assigned Examiner: to be assigned

Filed : April 7, 2004

Title : WAFER-LEVEL TESTING OF OPTICAL AND OPTOELECTRONIC

CHIPS

## Mail Stop Patent Application

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Applicants call attention to the attached Information
Disclosure Statement and documents listed on form PTO-1449.

This statement is being filed with the application.

Accordingly, only copies of foreign patent documents and nonpatent literature are enclosed. No fee is required.

The documents are in the English language; hence no concise explanation is necessary per Rule 98(a)(3).

Consideration of the foregoing and enclosures plus the return of a copy of the enclosed form PTO-1449 with the Examiner's initials in the left column per MPEP 609 are earnestly solicited along with an early action on the merits.

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Sheet	1	of	1

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 16696-003001	Application No. to be assigned
	losure Statement plicant	Applicant Gunn et al.	
(Use several sheets if necessary) (37 CFR §1.98(b))		Filing Date April 7, 2004	Group Art Unit to be assigned

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,500,540	03/19/1996	Jewell et al.			
	AB	5,631,571	05/20/1997	Spaziani et al.			
	AC	6,555,983	04/29/2003	Philip Andrew Davies			
	AD						
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	Foreign Patent Documents or Published Foreign Patent Applications							
Examiner	Desig.	Document	Publication	Country or			Trans	lation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)					
Examiner	Desig.				
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EXAMINER: Initials citation considered. Draw line through citation if no	of in conformance and not considered. Include conv of this form with
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